TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (U-MOS)

2SK3397

Relay Drive and DC-DC Converter Applications Motor Drive Applications

- Low drain-source ON resistance: $RDS(ON) = 4.0 \text{ m}\Omega \text{ (typ.)}$
- High forward transfer admittance: $|Y_{fs}| = 110 \text{ S (typ.)}$
- Low leakage current: $IDSS = 10 \mu A (max) (VDS = 30 V)$
- Enhancement-model: $V_{th} = 1.5 \text{ to } 3.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

Maximum Ratings (Tc = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	30	V	
Drain-gate voltage (Ro	$_{\rm GS} = 20 \text{ k}\Omega$)	V_{DGR}	30	V	
Gate-source voltage		V _{GSS}	±20	V	
Drain current	DC (Note 1)	I _D	70	А	
	Pulse (Note 1)	I _{DP}	210	A	
Drain power dissipatio	n	P _D	125	W	
Single pulse avalanche energy (Note 2)		E _{AS}	273	mJ	
Avalanche current		I _{AR}	70	Α	
Repetitive avalanche energy (Note 3)		E _{AR}	12.5	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55 to150	°C	

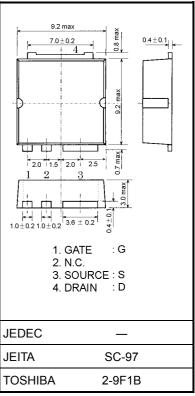
Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	1.0	°C/W

- Note 1: Please use devices on condition that the channel temperature is below 150°C.
- Note 2: $V_{DD}=25$ V, $T_{ch}=25^{\circ}C$ (initial), L=40 μH , $I_{AR}=70$ A, $R_{G}=25$ Ω
- Note 3: Repetitive rating: pulse width limited by maximum channel temperature

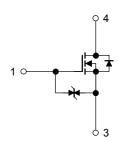
This transistor is an electrostatic sensitive device. Please handle with caution.

Unit: mm



Weight: 0.74 g (typ.)

Circuit Configuration



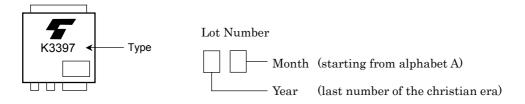
Electrical Characteristics (Tc = 25°C)

Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GSS}	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Drain cut-OFF cu	Drain cut-OFF current		V _{DS} = 30 V, V _{GS} = 0 V	_	_	10	μΑ
Drain-source breakdown voltage		V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	30	_	_	V
		V (BR) DSX	$I_D = 10 \text{ mA}, V_{GS} = -20 \text{ V}$	15	_	_	
Gate threshold voltage		V _{th}	V _{DS} = 10 V, I _D = 1 mA	1.5	_	30	V
Drain-source ON	resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 35 A	_	4.0	6.0	mΩ
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 35 A	55	110	_	S
Input capacitance		C _{iss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	5000	_	pF
Reverse transfer capacitance		C _{rss}		_	550	_	
Output capacitance		Coss		_	1000	_	
Switching time	Rise time	t _r	V_{GS} 0 V V_{GS} 0 V $0 V$	_	8.0	_	ns
	Turn-ON time	t _{on}		_	25	_	
	Fall time	t _f		_	48	_	
	Turn-OFF time	t _{off}		_	180	_	
Total gate charge (gate-source plus gate-drain)		Qg		_	110	_	nC
Gate-source charge		Q _{gs}	$V_{DD} \simeq 24 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 70 \text{ A}$	_	87	_	
Gate-drain ("miller") charge		Q _{gd}		_	23	_	

Source-Drain Ratings and Characteristics (Tc = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I_{DR}	_		_	70	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	210	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 70 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I _{DR} = 70 A, V _{GS} = 0 V,	_	40	_	ns
Reverse recovery charge	Qrr	dI _{DR} /dt = 30 A/μs	_	40	_	nC

Marking



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